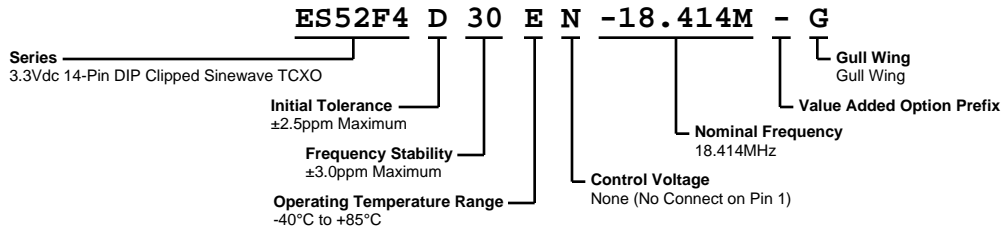


ES52F4D30EN-18.414M-G



ELECTRICAL SPECIFICATIONS

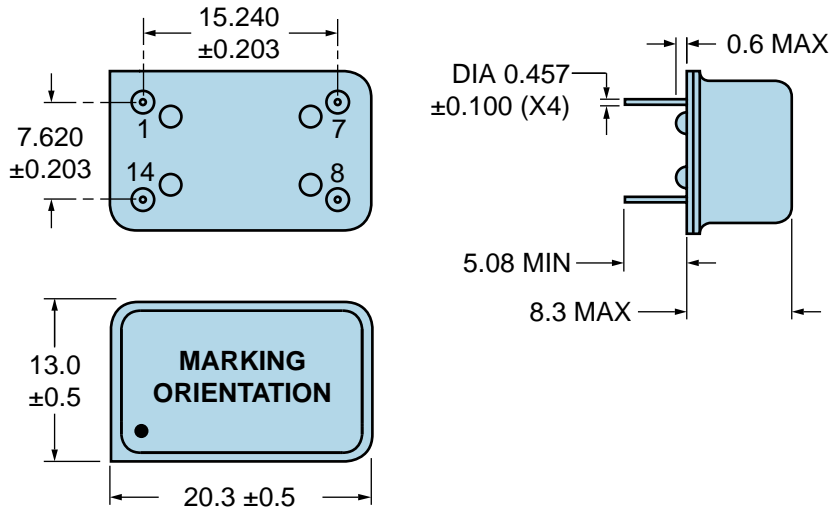
| | |
|---------------------------------------|--|
| Nominal Frequency | 18.414MHz |
| Initial Tolerance | ± 2.5 ppm Maximum (Measured at Nominal Vdd and Vc) |
| Frequency Stability | ± 3.0 ppm Maximum |
| Frequency Stability vs. Input Voltage | ± 0.3 ppm Maximum (Vdd $\pm 5\%$) |
| Frequency Stability vs. Aging | ± 1 ppm/Year Maximum (at 25°C) |
| Frequency Stability vs. Load | ± 0.2 ppm Maximum ($\pm 10\%$) |
| Operating Temperature Range | -40°C to $+85^{\circ}\text{C}$ |
| Supply Voltage | 3.3Vdc $\pm 5\%$ |
| Input Current | 10mA Maximum (Measured at Steady State at 25°C) |
| Output Voltage | 0.7Vp-p Minimum Clipped Sinewave |
| Load Drive Capability | 10kOhms//10pF |
| Output Logic Type | Clipped Sinewave |
| Control Voltage | None (No Connect on Pin 1) |
| Input Impedance | 10kOhms Typical |
| Phase Noise | -70dBc/Hz at 10Hz Offset, -100dBc/Hz at 100Hz Offset, -130dBc/Hz at 1kHz Offset, -140dBc/Hz at 10kHz Offset, -145dBc/Hz at 100kHz Offset (Typical Values at 19.440MHz) |
| Storage Temperature Range | -55°C to $+125^{\circ}\text{C}$ |

ENVIRONMENTAL & MECHANICAL SPECIFICATIONS

| | |
|------------------------------|--------------------------------------|
| Fine Leak Test | MIL-STD-883, Method 1014 Condition A |
| Gross Leak Test | MIL-STD-883, Method 1014 Condition C |
| Lead Integrity | MIL-STD-883, Method 2004 |
| Mechanical Shock | MIL-STD-202, Method 213 Condition C |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 |
| Resistance to Solvents | MIL-STD-202, Method 215 |
| Solderability | MIL-STD-883, Method 2003 |
| Temperature Cycling | MIL-STD-883, Method 1010 |
| Vibration | MIL-STD-883, Method 2007 Condition A |

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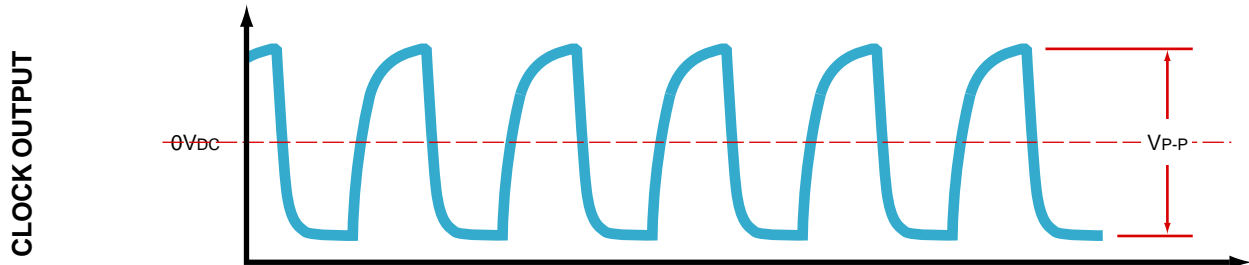
MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|-----|----------------|
| 1 | No Connect |
| 7 | Case Ground |
| 8 | Output |
| 14 | Supply Voltage |

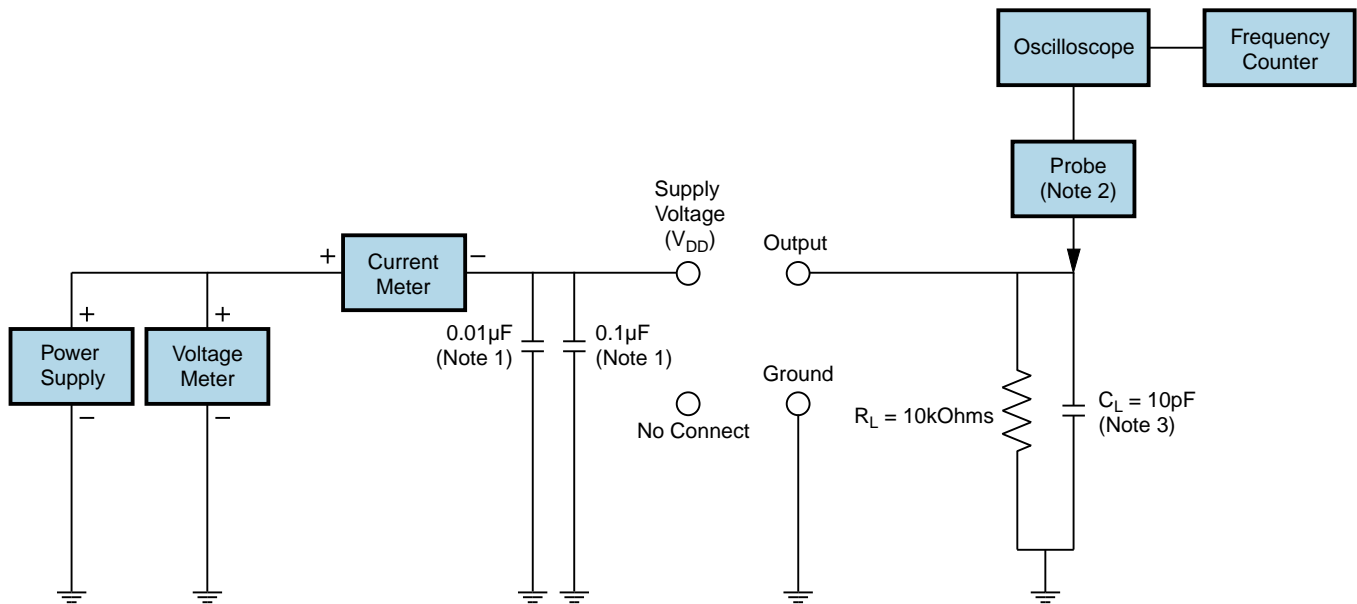
| LINE | MARKING |
|------|--|
| 1 | ECLIPTEK |
| 2 | 18.414M |
| 3 | XXYZZ <i>XX=Ecliptek Manufacturing Code</i> <i>Y=Last Digit of the Year</i> <i>ZZ=Week of the Year</i> |

OUTPUT WAVEFORM



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Test Circuit for No Connect Option



Note 1: An external 0.1µF low frequency tantalum bypass capacitor in parallel with a 0.01µF high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.

Recommended Solder Reflow Methods



Low Temperature Solder Bath (Wave Solder)

| | |
|--|---|
| T_s MAX to T_L (Ramp-up Rate) | 5°C/second Maximum |
| Preheat | |
| - Temperature Minimum (T_s MIN) | N/A |
| - Temperature Typical (T_s TYP) | 150°C |
| - Temperature Maximum (T_s MAX) | N/A |
| - Time (t_s MIN) | 30 - 60 Seconds |
| Ramp-up Rate (T_L to T_p) | 5°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T_L) | 150°C |
| - Time (t_L) | 200 Seconds Maximum |
| Peak Temperature (T_p) | 245°C Maximum |
| Target Peak Temperature (T_p Target) | 245°C Maximum 1 Time / 235°C Maximum 2 Times |
| Time within 5°C of actual peak (t_p) | 5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times |
| Ramp-down Rate | 5°C/second Maximum |
| Time 25°C to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.